



HY5V58B(L)F

4Banks x 8M x 8bits Synchronous DRAM

DESCRIPTION

The Hynix HY5V58B(L)F is a 268,435,456bit CMOS Synchronous DRAM, ideally suited for the main memory applications which require large memory density and high bandwidth. HY5V58B(L)F is organized as 4banks of 8,388,608x8.

HY5V58B(L)F is offering fully synchronous operation referenced to a positive edge of the clock. All inputs and outputs are synchronized with the rising edge of the clock input. The data paths are internally pipelined to achieve very high bandwidth. All input and output voltage levels are compatible with LVTTL.

Programmable options include the length of pipeline (Read latency of 2 or 3), the number of consecutive read or write cycles initiated by a single control command (Burst length of 1,2,4,8 or full page), and the burst count sequence(sequential or interleave). A burst of read or write cycles in progress can be terminated by a burst terminate command or can be interrupted and replaced by a new burst read or write command on any cycle. (This pipelined design is not restricted by a `2N` rule.)

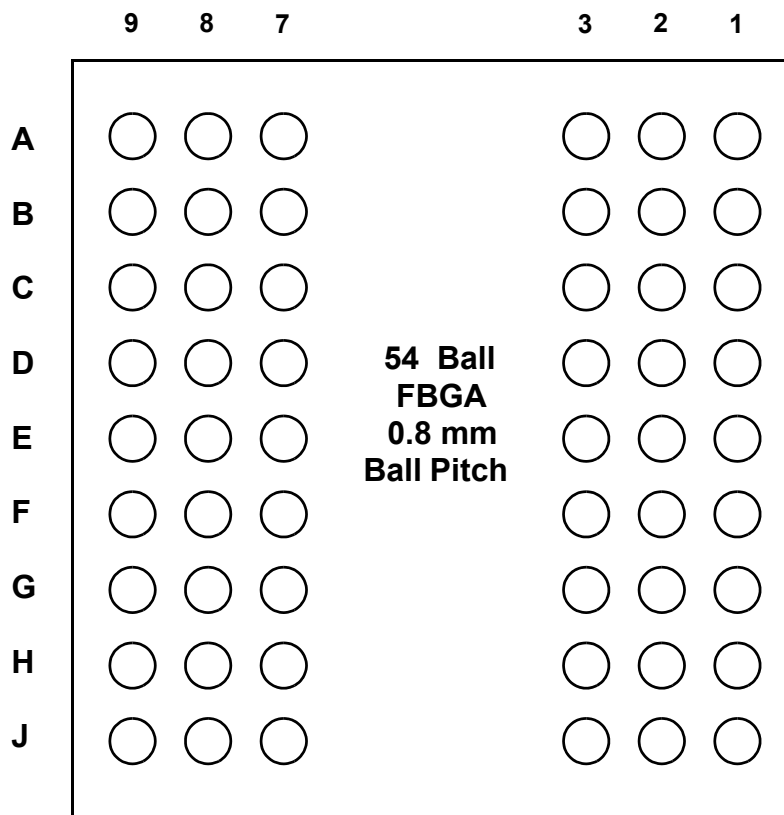
FEATURES

- Single 3.3±0.3V power supply
- All device Balls are compatible with LVTTL interface
- 54Ball FBGA With 0.8mm of ball pitch
- All inputs and outputs referenced to positive edge of system clock
- Data mask function by DQM
- Internal four banks operation
- Auto refresh and self refresh
- 8192 refresh cycles / 64ms
- Programmable Burst Length and Burst Type
 - 1, 2, 4, 8 or Full Page for Sequential Burst
 - 1, 2, 4 or 8 for Interleave Burst
- Programmable $\overline{\text{CAS}}$ Latency ; 2, 3 Clocks

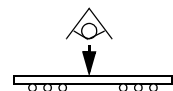
ORDERING INFORMATION

Part No.	Clock Frequency	Power	Organization	Interface	Package
HY5V58BF-H	133MHz	Normal	4Banks x 8Mbits x8	LVTTL	54ball FBGA
HY5V58BF-8	125MHz				
HY5V58BF-P	100MHz				
HY5V58BF-S	100MHz				
HY5V58B(L)F-H	133MHz	Low power			
HY5V58B(L)F-8	125MHz				
HY5V58B(L)F-P	100MHz				
HY5V58B(L)F-S	100MHz				

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BALL CONFIGURATION

< Bottom View >

1	2	3		7	8	9
VSS	DQ7	VSSQ	A	VDDQ	DQ0	VDD
NC	DQ6	VDDQ	B	VSSQ	DQ1	NC
NC	DQ5	VSSQ	C	VDDQ	DQ2	NC
NC	DQ4	VDDQ	D	VSSQ	DQ3	NC
NC	NC	VSS	E	VDD	NC	NC
DQM	CLK	CKE	F	/CAS	/RAS	/WE
A12	A11	A9	G	BA0	BA1	/CS
A8	A7	A6	H	A0	A1	A10
VSS	A5	A4	J	A3	A2	VDD

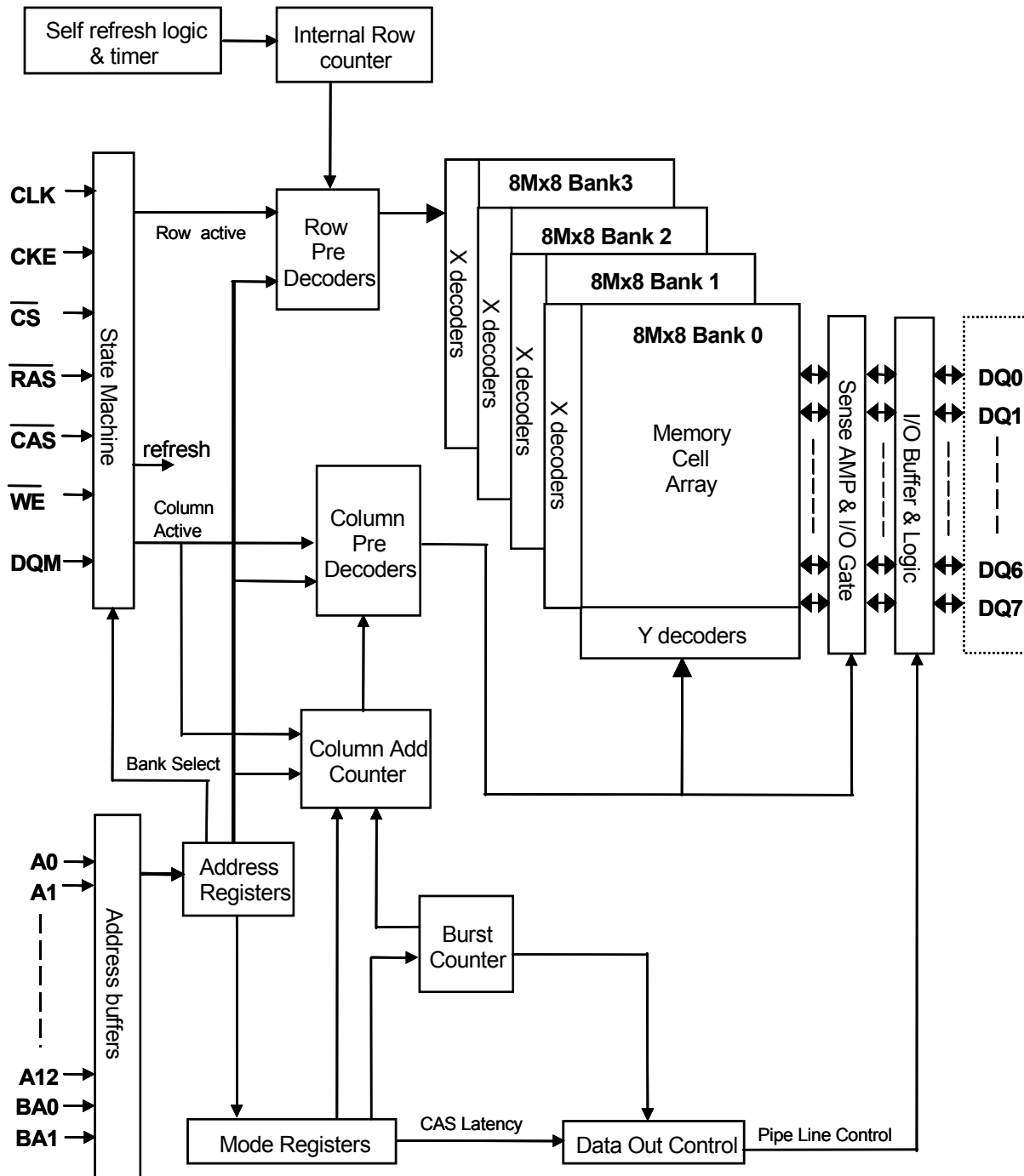
< Top View >


Ball DESCRIPTION

Ball	Ball NAME	DESCRIPTION
CLK	Clock	The system clock input. All other inputs are registered to the SDRAM on the rising edge of CLK
CKE	Clock Enable	Controls internal clock signal and when deactivated, the SDRAM will be one of the states among power down, suspend or self refresh
$\overline{\text{CS}}$	Chip Select	Enables or disables all inputs except CLK, CKE and DQM
BA0, BA1	Bank Address	Selects bank to be activated during $\overline{\text{RAS}}$ activity Selects bank to be read/written during $\overline{\text{CAS}}$ activity
A0 ~ A12	Address	Row Address : RA0 ~ RA12, Column Address : CA0 ~ CA9 Auto-precharge flag : A10
$\overline{\text{RAS}}$, $\overline{\text{CAS}}$, $\overline{\text{WE}}$	Row Address Strobe, Column Address Strobe, Write Enable	$\overline{\text{RAS}}$, $\overline{\text{CAS}}$ and $\overline{\text{WE}}$ define the operation Refer function truth table for details
DQM	Data Input/Output Mask	Controls output buffers in read mode and masks input data in write mode
DQ0 ~ DQ7	Data Input/Output	Multiplexed data input / output Ball
VDD/VSS	Power Supply/Ground	Power supply for internal circuits and input buffers
VDDQ/VSSQ	Data Output Power/Ground	Power supply for output buffers
NC	No Connection	No connection

FUNCTIONAL BLOCK DIAGRAM

4Mbit x 4banks x 8 I/O Synchronous DRAM



ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Rating	Unit
Ambient Temperature	TA	0 ~ 70	°C
Storage Temperature	TSTG	-55 ~ 125	°C
Voltage on Any Ball relative to VSS	VIN, VOUT	-1.0 ~ 4.6	V
Voltage on VDD relative to VSS	VDD, VDDQ	-1.0 ~ 4.6	V
Short Circuit Output Current	IOS	50	mA
Power Dissipation	PD	1	W
Soldering Temperature · Time	TSOLDER	260 · 10	°C · Sec

Note : Operation at above absolute maximum rating can adversely affect device reliability.

DC OPERATING CONDITION (TA=0 to 70°C)

Parameter	Symbol	Min	Typ	Max	Unit	Note
Power Supply Voltage	VDD, VDDQ	3.0	3.3	3.6	V	1
Input High voltage	VIH	2.0	3.0	VDDQ + 0.3	V	1,2
Input Low voltage	VIL	-0.3	0	0.8	V	1,3

Note :

- All voltages are referenced to VSS = 0V
- VIH(max) is acceptable 5.6V AC pulse width with <=3ns of duration.
- VIL(min) is acceptable -2.0V AC pulse width with <=3ns of duration.

AC OPERATING TEST CONDITION (TA=0 to 70°C, VDD=3.3±0.3V, VSS=0V)

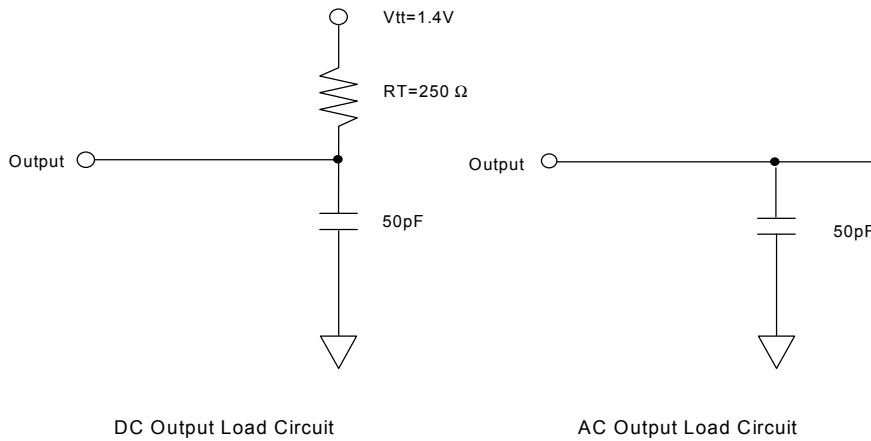
Parameter	Symbol	Value	Unit	Note
AC Input High / Low Level Voltage	VIH / VIL	2.4/0.4	V	
Input Timing Measurement Reference Level Voltage	Vtrip	1.4	V	
Input Rise / Fall Time	tR / tF	1	ns	
Output Timing Measurement Reference Level Voltage	Voutref	1.4	V	
Output Load Capacitance for Access Time Measurement	CL	50	pF	1

Note :

- Output load to measure access times is equivalent to two TTL gates and one capacitor (50pF). For details, refer to AC/DC output load circuit

CAPACITANCE (TA=25°C, f=1MHz)

Parameter	Ball	Symbol	-H		-8/P/S		Unit
			Min.	Max.	Min.	Max.	
Input Capacitance	CLK	CI1	2.5	3.5	2.5	4	pF
	A0 ~ A11, BA0, BA1, CKE, CS, RAS, CAS, WE, DQM	CI2	2.5	3.8	2.5	5	pF
Data Input / Output Capacitance	DQ0 ~ DQ7	CI/O	4	6.5	4	6.5	pF

OUTPUT LOAD CIRCUIT

DC CHARACTERISTICS I (TA=0 to 70°C, VDD=3.3±0.3V)

Parameter	Symbol	Min.	Max	Unit	Note
Input Leakage Current	ILI	-1	1	uA	1
Output Leakage Current	ILO	-1	1	uA	2
Output High Voltage	VOH	2.4	-	V	IOH = -2mA
Output Low Voltage	VOL	-	0.4	V	IOL = +2mA

Note :
 1.VIN = 0 to 3.6V, All other Balls are not under test = 0V
 2.DOUT is disabled, VOUT=0 to 3.6V

DC CHARACTERISTICS II (TA=0 to 70°C, VDD=3.3±0.3V, VSS=0V)

Parameter	Symbol	Test Condition	Speed				Unit	Note	
			-H	-8	-P	-S			
Operating Current	IDD1	Burst length=1, One bank active tRC ≥ tRC(min), IOL=0mA	120	120	110	110	mA	1	
Precharge Standby Current in Power Down Mode	IDD2P	CKE ≤ VIL(max), tCK = 15ns	2				mA		
	IDD2PS	CKE ≤ VIL(max), tCK = ∞	1						
Precharge Standby Current in Non Power Down Mode	IDD2N	CKE ≥ VIH(min), \overline{CS} ≥ VIH(min), tCK = 15ns Input signals are changed one time during 30ns. All other balls ≥ VDD-0.2V or ≤ 0.2V	15				mA		
	IDD2NS	CKE ≥ VIH(min), tCK = ∞ Input signals are stable.	15						
Active Standby Current in Power Down Mode	IDD3P	CKE ≤ VIL(max), tCK = 15ns	5				mA		
	IDD3PS	CKE ≤ VIL(max), tCK = ∞	5						
Active Standby Current in Non Power Down Mode	IDD3N	CKE ≥ VIH(min), \overline{CS} ≥ VIH(min), tCK = 15ns Input signals are changed one time during 30ns. All other balls ≥ VDD-0.2V or ≤ 0.2V	30				mA		
	IDD3NS	CKE ≥ VIH(min), tCK = ∞ Input signals are stable.	20						
Burst Mode Operating Current	IDD4	tCK ≥ tCK(min), IOL=0mA All banks active	CL=3	130	130	110	110	mA	1
			CL=2	140	140	120	120		
Auto Refresh Current	IDD5	tRRC ≥ tRRC(min), All banks active	220	200	200	200	mA	2	
Self Refresh Current	IDD6	CKE ≤ 0.2V	Normal	3				mA	3
			Low Power	1.5				mA	4

- Note :**
- 1.IDD1 and IDD4 depend on output loading and cycle rates. Specified values are measured with the output open.
 - 2.Min. of tRRC (Refresh RAS cycle time) is applied to HY5V58B(L)F-H/8/P/S which are listed on AC characteristic II.
 - 3.HY5V58BF-H/8/P/S
 - 4.HY5V58BLF-H/8/P/S

AC CHARACTERISTICS I (AC operating conditions unless otherwise noted)

Parameter		Symbol	-H		-8		-P		-S		Unit	Note
			Min	Max	Min	Max	Min	Max	Min	Max		
System Clock Cycle Time	$\overline{\text{CAS}}$ Latency = 3	tCK3	7.5	1000	8	1000	10	1000	10	1000	ns	
	$\overline{\text{CAS}}$ Latency = 2	tCK2	10		10		10		12		ns	
Clock High Pulse Width		tCHW	2.5	-	3	-	3	-	3	-	ns	1
Clock Low Pulse Width		tCLW	2.5	-	3	-	3	-	3	-	ns	1
Access Time From Clock	$\overline{\text{CAS}}$ Latency = 3	tAC3	-	5.4	-	6	-	6	-	6	ns	2
	$\overline{\text{CAS}}$ Latency = 2	tAC2	-	6	-	6	-	6	-	6	ns	
Data-Out Hold Time		tOH	2.7	-	3	-	3	-	3	-	ns	
Data-Input Setup Time		tDS	1.5	-	2	-	2	-	2	-	ns	1
Data-Input Hold Time		tDH	0.8	-	1	-	1	-	1	-	ns	1
Address Setup Time		tAS	1.5	-	2	-	2	-	2	-	ns	1
Address Hold Time		tAH	0.8	-	1	-	1	-	1	-	ns	1
CKE Setup Time		tCKS	1.5	-	2	-	2	-	2	-	ns	1
CKE Hold Time		tCKH	0.8	-	1	-	1	-	1	-	ns	1
Command Setup Time		tCS	1.5	-	2	-	2	-	2	-	ns	1
Command Hold Time		tCH	0.8	-	1	-	1	-	1	-	ns	1
CLK to Data Output in Low-Z Time		tOLZ	1	-	1	-	1	-	1	-	ns	
CLK to Data Output in High-Z Time	$\overline{\text{CAS}}$ Latency = 3	tOHZ3	2.7	5.4	3	6	3	6	3	6	ns	
	$\overline{\text{CAS}}$ Latency = 2	tOHZ2	3	6	3	6	3	6	3	6	ns	

Note :

1. Assume t_R / t_F (input rise and fall time) is 1ns
If $t_R \& t_F > 1\text{ns}$, then $[(t_R+t_F)/2-1]\text{ns}$ should be added to the parameter
2. Access times to be measured with input signals of 1v/ns edge rate, from 0.8v to 2.0v
If $t_R > 1\text{ns}$, then $(t_R/2-0.5)\text{ns}$ should be added to the parameter

AC CHARACTERISTICS II

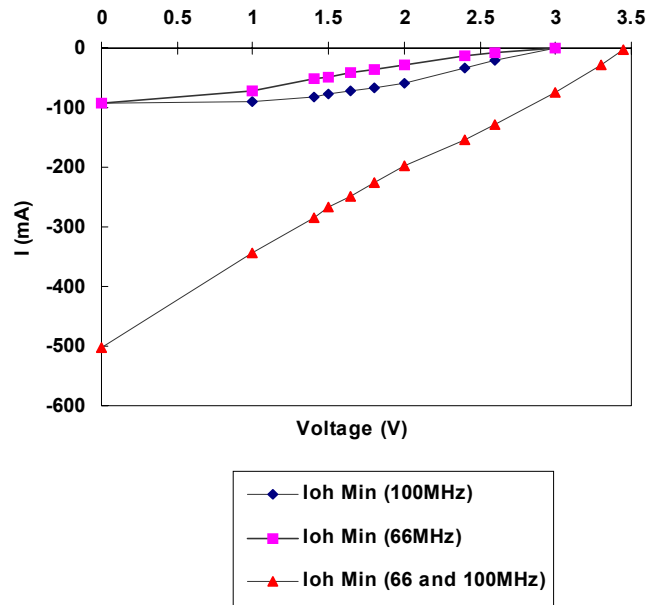
Parameter		Symbol	-H		-8		-P		-S		Unit	Note
			Min	Max	Min	Max	Min	Max	Min	Max		
$\overline{\text{RAS}}$ Cycle Time	Operation	tRC	65	-	68	-	70	-	70	-	ns	
	Auto Refresh	tRRC	65	-	68	-	70	-	70	-	ns	
$\overline{\text{RAS}}$ to $\overline{\text{CAS}}$ Delay		tRCD	20	-	20	-	20	-	20	-	ns	
$\overline{\text{RAS}}$ Active Time		tRAS	45	100K	48	100K	50	100K	50	100K	ns	
$\overline{\text{RAS}}$ Precharge Time		tRP	20	-	20	-	20	-	20	-	ns	
$\overline{\text{RAS}}$ to $\overline{\text{RAS}}$ Bank Active Delay		tRRD	15	-	16	-	20	-	20	-	ns	
$\overline{\text{CAS}}$ to $\overline{\text{CAS}}$ Delay		tCCD	1	-	1	-	1	-	1	-	CLK	
Write Command to Data-In Delay		tWTL	0	-	0	-	0	-	0	-	CLK	
Data-In to Precharge Command		tDPL	2	-	2	-	2	-	2	-	CLK	
Data-In to Active Command		tDAL	5	-	5	-	5	-	5	-	CLK	
DQM to Data-Out Hi-Z		tDQZ	2	-	2	-	2	-	2	-	CLK	
DQM to Data-In Mask		tDQM	0	-	0	-	0	-	0	-	CLK	
MRS to New Command		tMRD	2	-	2	-	2	-	2	-	CLK	
Precharge to Data Output Hi-Z	$\overline{\text{CAS}}$ Latency = 3	tPROZ3	3	-	3	-	3	-	3	-	CLK	
	$\overline{\text{CAS}}$ Latency = 2	tPROZ2	2	-	2	-	2	-	2	-	CLK	
Power Down Exit Time		tPDE	1	-	1	-	1	-	1	-	CLK	
Self Refresh Exit Time		tSRE	1	-	1	-	1	-	1	-	CLK	1
Refresh Time		tREF	-	64	-	64	-	64	-	64	ms	

Note :

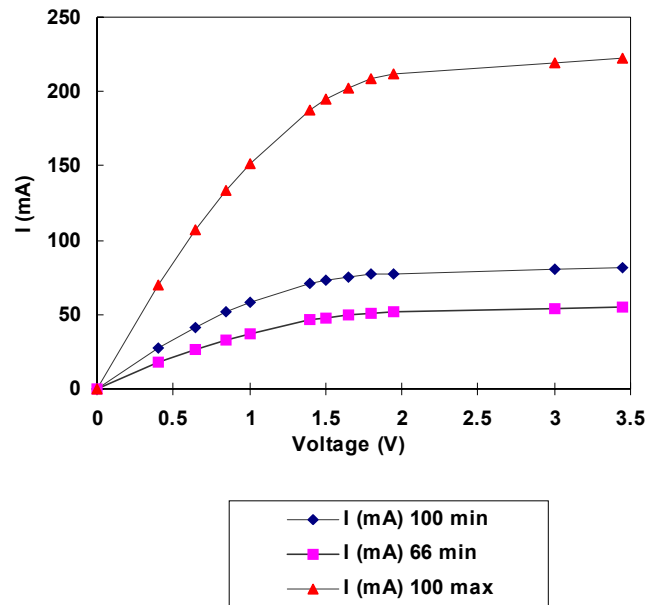
1. A new command can be given tRRC after self refresh exit.

IBIS SPECIFICATION
IOH Characteristics (Pull-up)

Voltage	100MHz Min	100MHz Max	66MHz Min
(V)	I (mA)	I (mA)	I (mA)
3.45		-2.4	
3.3		-27.3	
3.0	0.0	-74.1	-0.7
2.6	-21.1	-129.2	-7.5
2.4	-34.1	-153.3	-13.3
2.0	-58.7	-197.0	-27.5
1.8	-67.3	-226.2	-35.5
1.65	-73.0	-248.0	-41.1
1.5	-77.9	-269.7	-47.9
1.4	-80.8	-284.3	-52.4
1.0	-88.6	-344.5	-72.5
0.0	-93.0	-502.4	-93.0

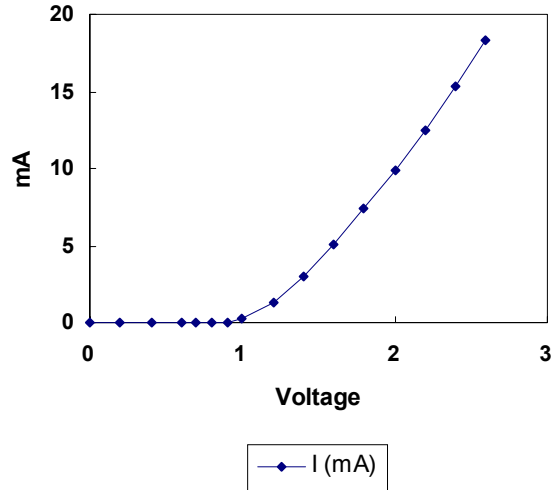
66MHz and 100MHz Pull-up

IOI Characteristics (Pull-down)

Voltage	100MHz Min	100MHz Max	66MHz Min
(V)	I (mA)	I (mA)	I (mA)
0.0	0.0	0.0	0.0
0.4	27.5	70.2	17.7
0.65	41.8	107.5	26.9
0.85	51.6	133.8	33.3
1.0	58.0	151.2	37.6
1.4	70.7	187.7	46.6
1.5	72.9	194.4	48.0
1.65	75.4	202.5	49.5
1.8	77.0	208.6	50.7
1.95	77.6	212.0	51.5
3.0	80.3	219.6	54.2
3.45	81.4	222.6	54.9

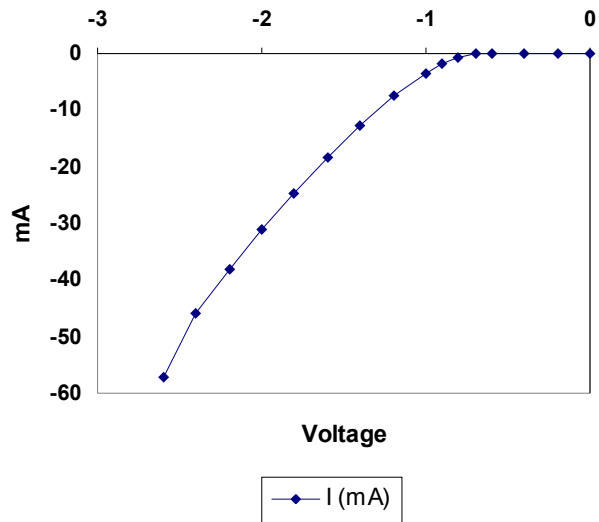
66MHz and 100MHz Pull-down


VDD Clamp @ CLK, CKE, \overline{CS} , DQM & DQ

VDD (V)	I(mA)
0.0	0.0
0.2	0.0
0.4	0.0
0.6	0.0
0.7	0.0
0.8	0.0
0.9	0.0
1.0	0.23
1.2	1.34
1.4	3.02
1.6	5.06
1.8	7.35
2.0	9.83
2.2	12.48
2.4	15.30
2.6	18.31

**Minimum VDD clamp current
(Referenced to VDD)**

VSS Clamp @ CLK, CKE, \overline{CS} , DQM & DQ

VSS (V)	I (mA)
-2.6	-57.23
-2.4	-45.77
-2.2	-38.26
-2.0	-31.22
-1.8	-24.58
-1.6	-18.37
-1.4	-12.56
-1.2	-7.57
-1.0	-3.37
-0.9	-1.75
-0.8	-0.58
-0.7	-0.05
-0.6	0.0
-0.4	0.0
-0.2	0.0
0.0	0.0

Minimum VSS clamp current


DEVICE OPERATING OPTION TABLE
HY5V58B(L)F-H

	CAS Latency	tRCD	tRAS	tRC	tRP	tAC	tOH
133MHz(7.5ns)	3CLKs	3CLKs	6CLKs	9CLKs	3CLKs	5.4ns	2.7ns
125MHz(8ns)	3CLKs	3CLKs	6CLKs	9CLKs	3CLKs	6ns	3ns
100MHz(10ns)	2CLKs	2CLKs	5CLKs	7CLKs	2CLKs	6ns	3ns

HY5V58B(L)F-8

	CAS Latency	tRCD	tRAS	tRC	tRP	tAC	tOH
125MHz(8ns)	3CLKs	3CLKs	6CLKs	9CLKs	3CLKs	6ns	3ns
100MHz(10ns)	2CLKs	2CLKs	5CLKs	7CLKs	2CLKs	6ns	3ns
83MHz(12ns)	2CLKs	2CLKs	4CLKs	6CLKs	2CLKs	6ns	3ns

HY5V58B(L)F-P

	CAS Latency	tRCD	tRAS	tRC	tRP	tAC	tOH
100MHz(10ns)	2CLKs	2CLKs	5CLKs	7CLKs	2CLKs	6ns	3ns
83MHz(12ns)	2CLKs	2CLKs	5CLKs	7CLKs	2CLKs	6ns	3ns
66MHz(15ns)	2CLKs	2CLKs	4CLKs	6CLKs	2CLKs	6ns	3ns

HY5V58B(L)F-S

	CAS Latency	tRCD	tRAS	tRC	tRP	tAC	tOH
100MHz(10ns)	3CLKs	2CLKs	5CLKs	7CLKs	2CLKs	6ns	3ns
83MHz(12ns)	2CLKs	2CLKs	5CLKs	7CLKs	2CLKs	6ns	3ns
66MHz(15ns)	2CLKs	2CLKs	4CLKs	6CLKs	2CLKs	6ns	3ns

COMMAND TRUTH TABLE

Command		CKEn-1	CKEn	\overline{CS}	\overline{RAS}	\overline{CAS}	\overline{WE}	DQM	ADDR	A10/ AP	BA	Note
Mode Register Set		H	X	L	L	L	L	X	OP code			1
No Operation		H	X	H	X	X	X	X	X			
				L	H	H	H					
Bank Active		H	X	L	L	H	H	X	RA		V	
Read		H	X	L	H	L	H	X	CA	L	V	
Read with Autoprecharge										H		
Write		H	X	L	H	L	L	X	CA	L	V	
Write with Autoprecharge										H		
Precharge All Banks		H	X	L	L	H	L	X	X	H	X	
Precharge selected Bank										L	V	
Burst Stop		H	X	L	H	H	L	X	X			
DQM		H	X					V	X			
Auto Refresh		H	H	L	L	L	H	X	X			
Burst-Read-Single-WRITE		H	X	L	L	L	L	X	A9 Ball High (Other Balls OP code)			MRS Mode
Self Refresh	Entry	H	L	L	L	L	H	X	X			
	Exit	L	H	H	X	X	X	X				
				L	H	H	H					
Precharge power down	Entry	H	L	H	X	X	X	X	X			
				L	H	H	H					
	Exit	L	H	H	X	X	X	X				
				L	H	H	H					
Clock Suspend	Entry	H	L	H	X	X	X	X	X			
				L	V	V	V					
	Exit	L	H	X				X				

- Note :**
1. OP Code : Operand Code
 2. V = Valid, X = Dont care, H = Logic High, L= Logic Low, RA = Row Address, CA = Column Address.
 3. The burst read single write mode is entered by programming the write burst mode bit (A9) in the mode register to a logic 1.

PACKAGE INFORMATION

54 Ball 0.8mm pitch 8.0mm x 13.5mm FBGA

